

Specification & Features

▷ ST5030SL

Measurement range	100 Å ~ 35 μm (Depends on film)
Measurement speed	1~2 sec/site
Stage size	300mm X 300mm
Measuring sample size	4~12"
Spot size	40 μm/20 μm, 4 μm(option)
Measurement principle	Reflectometer
Measurement method	Non-contact
Type	Automatic
Dimension	500 x 750 x 650 mm
Weight	100Kg
Illumination	12v 100w Halogen lamp
Option	Reference Samples Anti-vibration Table



Features

Fast Measurement & Easy Operation
 Non-contact & Non-destructive
 Superb Repeatability & Reproducibility
 Windows based user-friendly interface
 Print function of each view & data saving
 2D / 3D Mapping & Contouring
 Automatic stage control & Anti-vibration table
 CCD Camera
 Auto Focusing

Application

All capability of ST2000 & more precision measurement
 Intended for large size wafer measurement